

Product data sheet

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- Solid-state silicon-avalanche technology
- Low operating and clamping voltage
- Up to four I/O Lines of Protection
- Ultra low capacitance: 0.5pF typical(I/O to I/O)
- Low Leakage
- Low operating voltage:3.3V
- Flow-Through design

IEC COMPATIBILITY (EN61000-4)

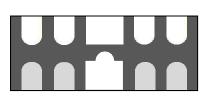
- IEC 61000-4-2 (ESD) ±15kV (air), ±8kV (contact)
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 5A (8/20µs)

Mechanical Characteristics

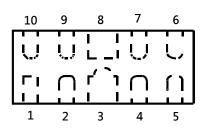
- Molding compound flammability rating: UL 94V-0
- Marking: Marking Code
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

Applications

- Digital Visual Interface(DVI)
- MDDI Ports
- DisplayPortTM Interface
- PCI Express
- High Definition Multi-Media Interface(HDMI)
- eSATA Interfaces



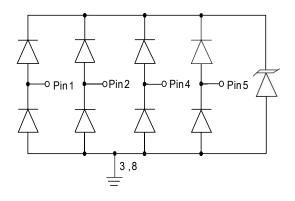
uSON-10



Schematic & PIN Configuration

Pin	Identificaion	
1,2,4,5	Input Lines	
6,7,9,10	Output Lines (No Internal Connection)	
3,8	Ground	

Circuit Diagram



4-Line Protection



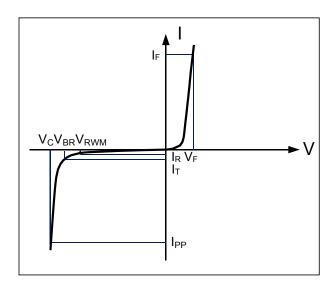
TPD4E05U06DQAR-MS

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Rating	Symbol	Value	Units
Peak Pulse Power (t _p =8/20µs)	P _{PP}	150	Watts
Peak Pulse Current (t _p =8/20µs)	I _{pp}	5	А
ESD per IEC 61000-4-2(Air) ESD per IEC 61000-4-2(contact)	V _{ESD}	+/-17 +/-12	kV
Operating Temperature	TJ	-55 to + 125	°C
Storage Temperature	T _{STG}	-55 to +150	°C

Electrical Parameters (T=25°C)

Symbol	Parameter			
Ірр	Maximum Reverse Peak Pulse Current			
Vc	Clamping Voltage @ IPP			
VRWM	Working Peak Reverse Voltage			
IR	Maximum Reverse Leakage Current @ VRWM			
VBR	Breakdown Voltage @ I⊤			
Iτ	Test Current			
lF	Forward Current			
VF	Forward Voltage @ I _F			



Electrical Characteristics

Parameter	Symbol	Conditions	Minimum	Typical	Maximum	Units
Reverse Stand-Off Voltage	V _{RWM}	Any I/O pin to ground			3.3	V
Reverse Breakdown Voltage	V _{BR}	I _t = 1mA Any I/O pin to ground	6.0			V
Reverse Leakage Current	I _R	V _{RWM} = 5V, T=25°C Any I/O pin to ground			1	μA
Clamping Voltage	Vc	l _{pp} =5A, t _p =8/20µs Any I/O pin to ground			15	V
		V _R = 0V, f = 1MHz I/O pin to GND			0.8	pF
Junction Capacitance	Cj	V _R = 0V, f = 1MHz Between I/O pins		0.3		pF



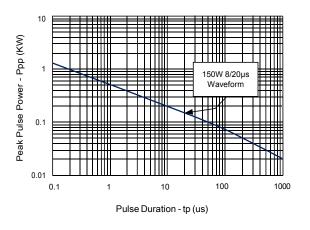


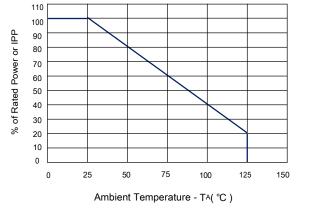
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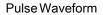
Typical Characteristics

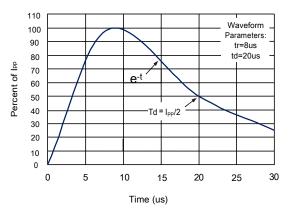
Non-Repetitive Peak Pulse Power vs. Pulse Time

Power Derating curve

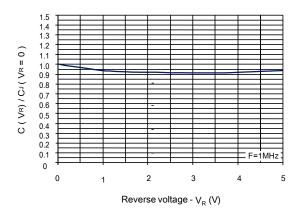




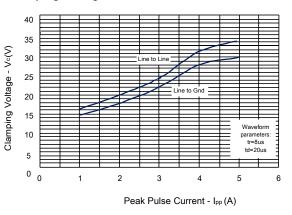




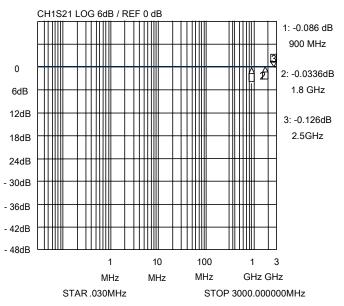
Normalized Capacitance vs. Reverse Voltage



Clamping Voltage vs.Peak Pulse Current



Insertion Loss S21 - I/O to GND

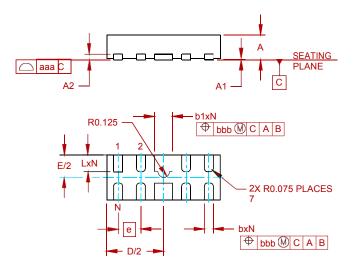




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PACKAGE MECHANICAL DATA

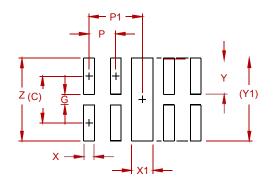


Dimensions in millimeters

A	✓ D →	В
		E t

			1	ONE			
DIMENSI ONS							
ЫМ	INC	HES		MILLIN	MILLIMETERS		
2	MIN	NOM	MAX	MIN	NOM	MAX	
A	.020	.023	.026	0.50	0.58	0.65	
A1	0.00	.001	.002	0.00	0.03	0.05	
A2	(.005)		(0	.13)			
b	.006	.008	.010	0.15	0.20	0.25	
b1	.014	.016	.018	0.35	0.40	0.45	
D	.094	.098	.102	2.40	2.50	2.60	
E	.035	.039	.043	0.90	1.00	1.10	
е	.020 BSC		0.50	BSC	-		
L	.012	.015	.017	0.30	0.38	0.425	
N	8			8			
aaa	.003		0.08				
bbb	.004		.004 0.10				

Suggested Pad Layout



	DIMENSIONS				
DIM	INCHES	MILLIMETERS			
С	(.034)	(0.875)			
G	.008	0.20			
Р	.020	0.50			
P1	.039	1.00			
Х	.008	0.20			
X1	.016	0.40			
Y	.027	0.675			
Y1	(.061)	(1.55)			
Z	.061	1.55			

NOTES:

CONTROLLING DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES). THIS LAND PATTERN IS FOR REFERENCE PURPOSES ONLY. CONSULT YOUR MANUFACTURING GROUP TO ENSURE YOUR COMPANY'S MANUFACTURING GUIDELINES ARE MET.

REEL SPECIFICATION

P/N	PKG	QTY
TPD4E05U06DQAR-MS	uSON-10	3000





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